

## Single Event Effect Microchip Testing at the Texas A&M University Cyclotron Institute

Dr. Henry Clark SEELine Project Manager <u>http://cyclotron.tamu.edu/ref/</u>



Effects from radiation on Microchips: SEE – Single Event Effect Dose – Total Dose from ionizing radiation

Electromagnetic (UV, x-rays, y-rays) – Dose

**Electrons – Dose** 

**Neutrons - Dose** 

Light ions (protons, alphas) – Dose, SEE

Heavy ions (N, O, Ne, Ar, Fe...U) – SEE (mainly), Dose

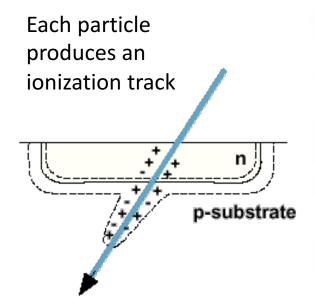


## **SEE definitions:**

- A single event upset (SEU) is a change of state caused by one single ionizing particle (ions, electrons, photons...) striking a sensitive node in a micro-electronic device.
- Soft errors are non-destructive and normally appear as transient pulses in logic or support circuitry, or as bit flips in memory cells or registers.
- Hard errors usually result in a high operating current, above device specifications, and must be cleared by a power reset. Burnout errors are so destructive that the device becomes operationally dead.



#### **Example of Hard Error or Gate Rupture of MOSFET device.**



Reroutes the flow of electrons of the device – causing charge and voltage changes

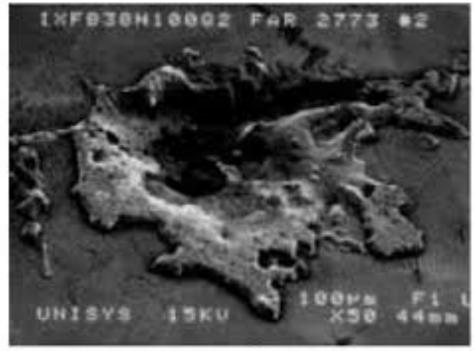
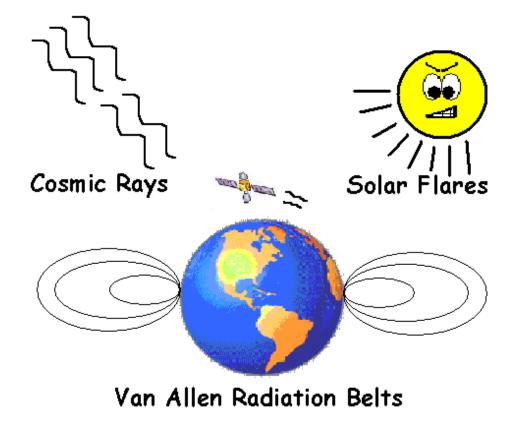


Figure 2: SEM image of failed MOSFET chip



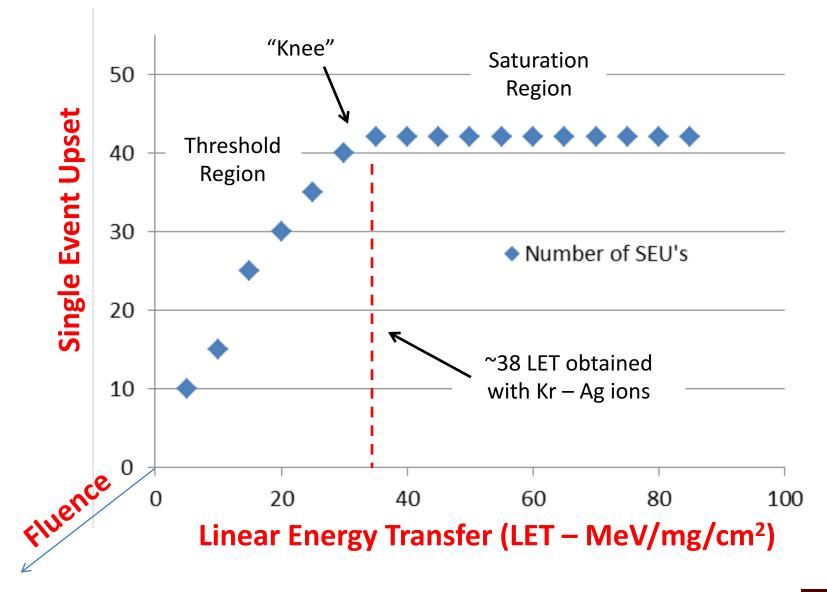
## **Space Radiation Effects:**



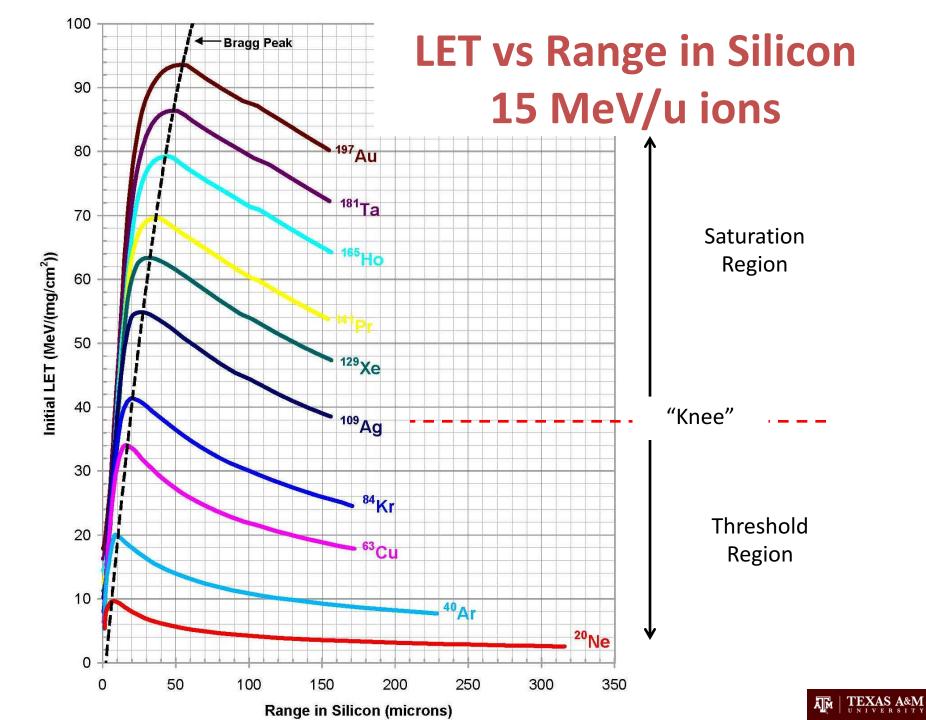
- Aerospace computer equipment receives radiation from cosmic rays, solar flares and the Earth's Van Allen radiation Belts - causing SEUs.
- Engineers must test the resilience of their computer chips in accelerated beams here on Earth to simulate the effects that will happen in space.

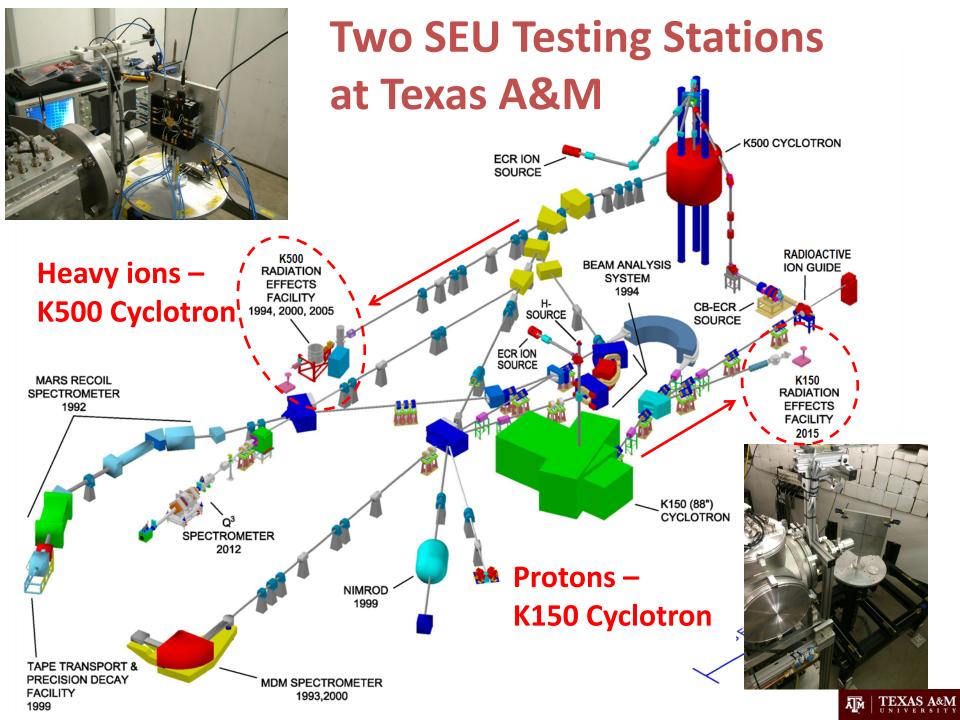


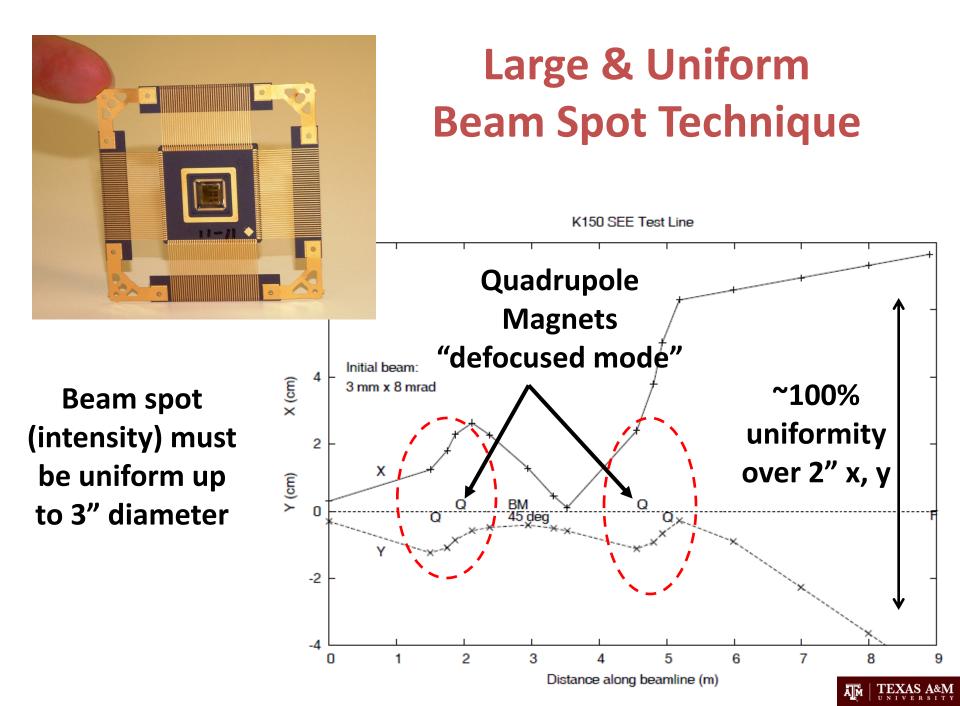
## **Typical SEU "Soft Error" Cross Section**









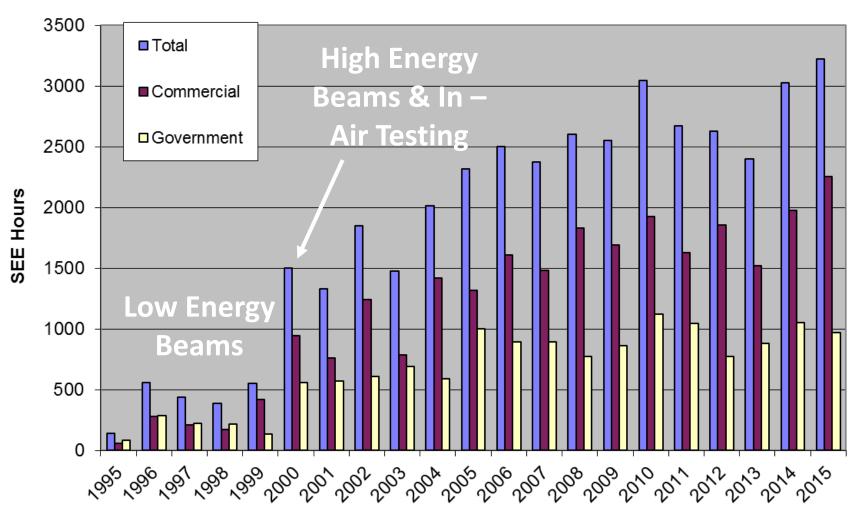


## History of SEU Testing at Texas A&M

- Began in 1995 with 10 MeV/u heavy ions, but with a limited list of beams
- Added high energy series (15, 25, 40 & 55 MeV/u) over years 1997-2005 (15 MeV/u is offered from <sup>4</sup>He to <sup>197</sup>Au)
- Offered "in-air" testing in year 2000 usage hours increased from ~500/yr to ~2500/yr
- Usage hours have remained steady at >2500 hours since year 2006
- Usage by 1/3 Government/University and 2/3 Commercial agencies has remained consistent
- Usage by international agencies continues to increase (France, Japan, Italy, Korea, Singapore, Canada)
- In 2015, added K150 proton testing beam line (~1 50 MeV)



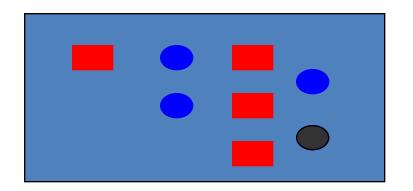
## **SEU Testing Hours at Texas A&M**



Year





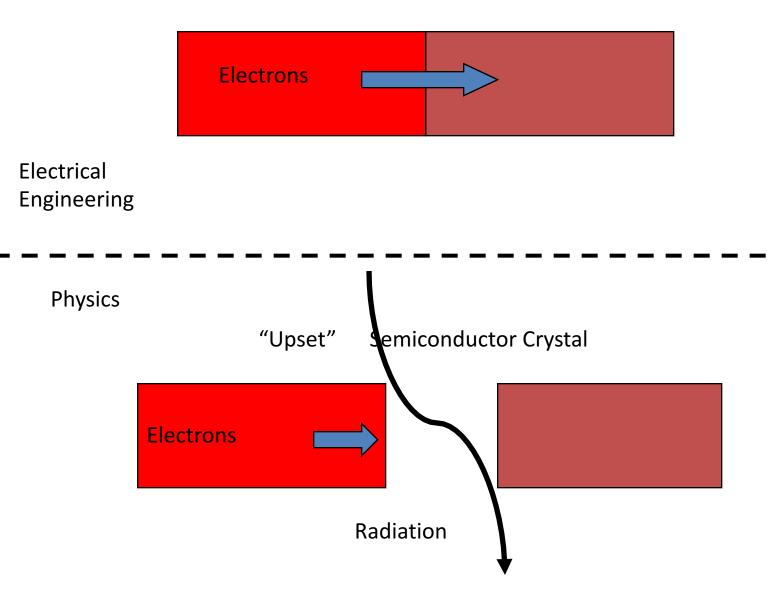


### Circuit 20 years ago – "inches"



#### Integrated Circuit Today – "microns"

Normal Semiconductor Crystal



## **Single Event Upset Testing Agencies...**

3D Plus Actel Corporation Aeroflex Aerospace Corp. Air Force Airbus - France AMTEC Applied Nanotech ARIA ARO ASTRUM - Germany ATK Mission Research ATMEL - France BAE Systems Ball Aerospace Bionetics Blue Line Engineering Boeing (Seattle) Boeing Satellite Systems Broadcom Communications CAMBR CEA - France Cisco Systems Cobham (RAD) Custom Test Sys Data Devices Inc Defense Threat Reduction Agency DRS Sensors DSO-Singapore EM Photonics Ensign-Bickford European Space Agency

Freebird Fuji Electric - Japan Full Circle Research General Dynamics Georgia Tech University GNSS-Norway Harris Semiconductor HIREX - France Honevwell Hughes Space Communications IBM ICS Radiation IMT - Italv InnoFlight InnoFlight Innovative Concepts, Inc. INTA Intel Corporation International Rectifier Intersil Corporation IRCOS IRCOS ITT Aerospace ITT Communications JAXA - Japan JD Instruments Johns Hopkins KAIST - Korea L-3 Communications Lockheed Martin Los Alamos National Laboratory Makel Engineering

Maxwell Engineering McDonnell-Douglas MD Robotics MDA Corp Michigan State University - NSCL Micro RDC MicroSat - Canada Microsemi Millennium Space Mitsubishi Heavy Industries Montana State University Motorola Corporation MSEI NASA-Goddard Space Flight Center NASA-Jet Propulsion Laboratory NASA-Johnson Space Center National Semiconductor Naval Research Laboratory Naval Surface Warfare Center Northrop Grumman Novous Technologies OptiComp Corp Orbital ATK Peregrine Semiconductor Prairie View A&M University Radiation Assured Devices Radiation Group Raytheon Corporation RES LLC Rvoei - Japan SAIC Sandia National Laboratory

Save Inc Scientic SEAKR Engineering SEMICOA Signal Analysis Silicon Space Technologies Silicon Turnkey Solutions SOREQ - Israel Southwest Research Institute Stapor Research Star Vision Sun Tronics T2 Research Teledyne DALSA TAMU Physics Department Texas Instruments Thales Alenia Space - France TRAD - France United Space Alliance University of Colorado University of Idaho University of Maryland University of Michigan University of Saskatchewan University of Texas - El Paso Utah State University Vanderbilt University VPT Inc White Sands Applied Research Laboratory Woosong University - Korea Xilinx Corporation



## Possible job opportunity at NASA GSFC...

Hi Henry –

I may be in the market for a physicist/engineer interested in working in our accelerator lab (two Van de Graaffs and one electrostatic machine). We do some single-event testing, though most of the work is dedicated to space physics flight instrument calibration (e.g., measures solar wind, magnetically-trapped particles, etc.) and dielectric charging characterization. Within the facility, we also operate high-energy gamma sources for ionizing dose testing. The accelerator facility is attached to the larger Radiation Effects and Analysis Group.

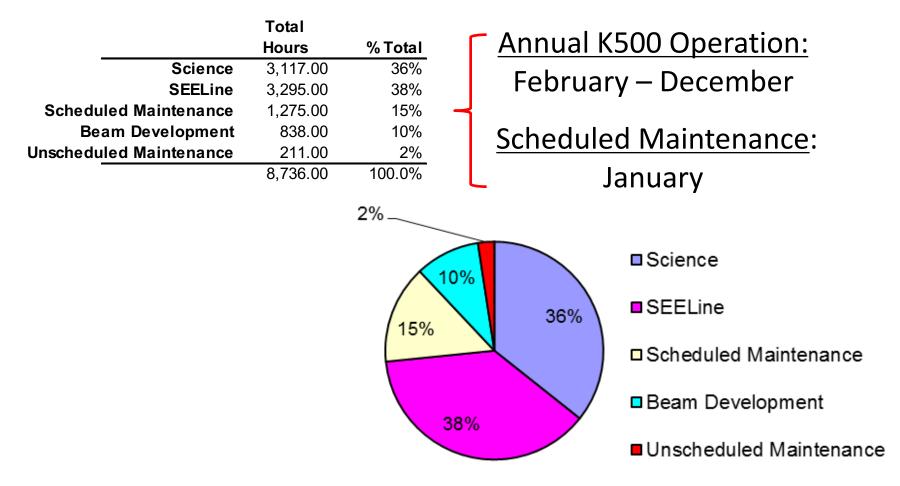
Anyway, if you know of some good candidates please drop me a note. I can provide more details if requested, though we are at the very early stages, so there is still more to work out.

Many thanks, Jonny

Jonathan Pellish Code 560, Acting Associate Chief Electrical Engineering Division NASA Goddard Space Flight Center



## Texas A&M Cyclotron Institute K500 Operational Hours





	Monday	Tuesday	Wednesday	Thursday	Friday	Saturday	Sunday
hours 000	6-Feb Shut Down	7-Feb	8-Feb	9-Feb	10-Feb	11-Feb	12-Feb
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	Monday	Tuesday	Wednesday	Thursday	Friday	Saturday	Sunday
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0800							NASA GSFC SEE Line
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	v'				v	Development	Developmen
0800	Boeing Sat Sys SEE Line	i V	i V	l V	PVAMU SEE Line	NASA JSC SEE Line	
1600		Raytheon	Lock Mart	Beam			
	v	SEE Line	SEE Line	Development	v	v	v

#### **Typical Beam Schedule:**

- 1 2 weeks SEU
  Testing (yellow)
- 1 2 weeks of
  Science Experiments
  (all other colors)
- Schedule 6 8 weeks in advance

#### **Accelerator Physics Group**

**Dr. Henry Clark** Dr. Don May Dr. George Kim **Dr. Greg Chubarian** Dr. Gabriel Tabacaru Dr. Vladimir Horvat Dr. Brian Roeder **Mr. Bruce Hyman Mr. Joe Brinkley** Mr. Stephen Gerlt





# Visit our website at <a href="http://cyclotron.tamu.edu/ref/">http://cyclotron.tamu.edu/ref/</a>

Questions, contracting, scheduling contact Henry Clark at <u>clark@comp.tamu.edu</u>

